

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination NAKAZAWA ET AL.	
			Examiner David A. Zerneke	Art Unit 2827	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,351,872	10-1994	Kobayashi, Hiroaki	228/6.2
*	B	US-5,641,714	06-1997	Yamanaka, Hideo	438/14
*	C	US-5,110,393	05-1992	Sumi et al.	156/344
*	D	US-6,338,980	01-2002	Satoh, Tetsuo	438/106
*	E	US-6,107,164	08-2000	Ohuchi, Shinji	438/465
*	F	US-6,083,811	07-2000	Riding et al.	438/460
*	G	US-5,312,505	05-1994	Sumi et al.	156/584
*	H	US-5,000,814	03-1991	Sumi, Sigeo	156/344
*	I	US-4,915,757	04-1990	Rando, Joseph F.	156/64
*	J	US-4,867,836	09-1989	Hamamura et al.	156/584
*	K	US-4,770,737	09-1988	Seki, Mitsuhiro	156/584
*	L	US-5,358,591	10-1994	Candore, Amedeo	156/344
*	M	US-6,500,298	12-2002	Wright et al.	156/344

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.